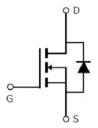


Main Product Characteristics:

V _{DSS}	800V
R _{DS} (on)	3.7Ω (typ.)
I _D	3A







TO220F

Marking and pin
Assignment

Schematic diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute max Rating:

Symbol	Parameter	Max.	Units	
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V①	3		
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V①	1.9	Α	
I _{DM}	Pulsed Drain Current②	12		
P _D @TC = 25°C	Power Dissipation③	39	W	
PD @ 10 = 25 C	Linear Derating Factor	0.31	W/°C	
V _{DS}	Drain-Source Voltage	800	V	
V _{GS}	Gate-to-Source Voltage		V	
Eas	Single Pulse Avalanche Energy @ L=67mH		mJ	
I _{AS}	Avalanche Current @ L=67mH	3.1	А	
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C	



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-case③	_	3.2	°C/W
В	Junction-to-ambient (t \leq 10s) (4)	_	62.5	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④		40	°C/W

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	800	_	_	V	V _{GS} = 0V, ID = 250μA
D	D 01 15 D 1 1 1 0	_	3.7	4.8	0	V _{GS} =10V,I _D = 1.5A
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	8.7	_	Ω	T _J = 125 ℃
V	Cata threehold voltage	2	_	4	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
$V_{GS(th)}$	Gate threshold voltage	_	2.6	_	V	T _J = 125℃
	Drain to Course leeke se gurrent	_	_	1		$V_{DS} = 800V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source leakage current	_	_	50	μA	T _J = 125℃
1	Cata to Source forward lookage	_	_	100	n A	V _{GS} =30V
I _{GSS}	Gate-to-Source forward leakage	_	_	-100	nA	V _{GS} = -30V
Q_g	Total gate charge	_	11.2	_	nC	$I_D = 3A$,
Q_{gs}	Gate-to-Source charge	_	3.3	_		V _{DS} =400V,
Q_{gd}	Gate-to-Drain("Miller") charge	_	5.1	_		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	12.4	_	V _{GS} =10V, VDS=400V	
t _r	Rise time	_	19.1	_		$R_L=130\Omega$,
t _{d(off)}	Turn-Off delay time	_	24.4	_	ns	R _{GEN} =25Ω
t _f	Fall time		16.7	_		ID=3A
C _{iss}	Input capacitance	_	404	_		$V_{GS} = 0V$
Coss	Output capacitance	_	54.4	_	pF	V _{DS} = 25V
C _{rss}	Reverse transfer capacitance	_	4.75	_		f = 1MHz

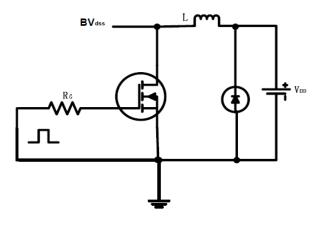
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
1	Continuous Source Current			3	۸	MOSFET symbol
Is	(Body Diode)	_		3	A	showing the
	Pulsed Source Current		_	12	А	integral reverse
I _{SM}	(Body Diode)	_				p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.86	1.4	V	I _S =3A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	989	_	ns	$T_J = 25^{\circ}C, I_F = 3A,$
Q _{rr}	Reverse Recovery Charge	_	2405	_	nC	di/dt = 100A/µs

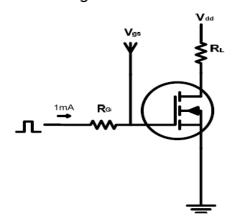


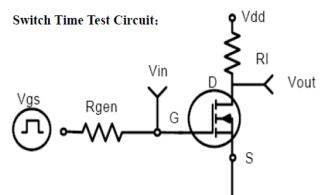
Test circuits and Waveforms

EAS test circuits:

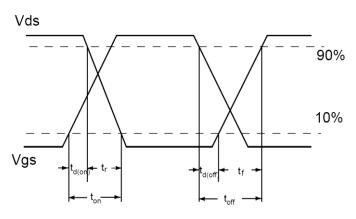


Gate charge test circuit:





Switch Waveforms:

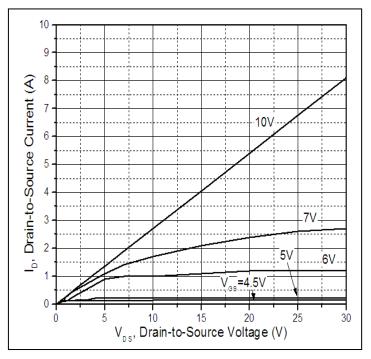


Notes:

- ①The maximum current rating is limited by bond-wires.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of $R_{\theta JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Typical electrical and thermal characteristics



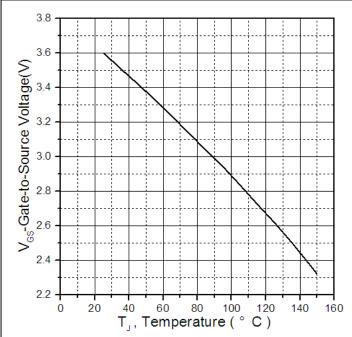


Figure 1: Typical Output Characteristics

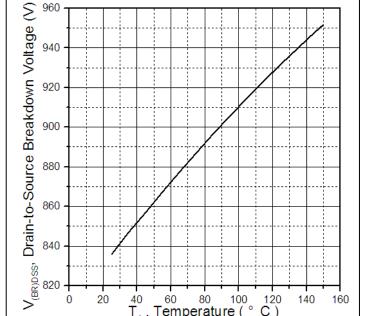


Figure 3. Drain-to-Source Breakdown Voltage Vs. **Case Temperature**

120 C)

140

160

 ${\mathsf T}_{_{\mathsf J}}^{40}$, ${\mathsf T}_{\mathsf emperature}^{60}$ (80

Figure 2. Gate to source cut-off voltage

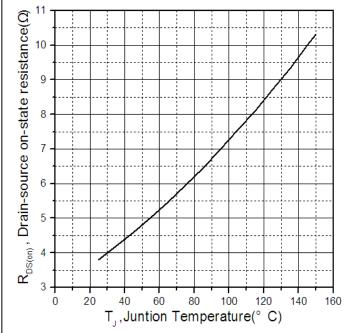


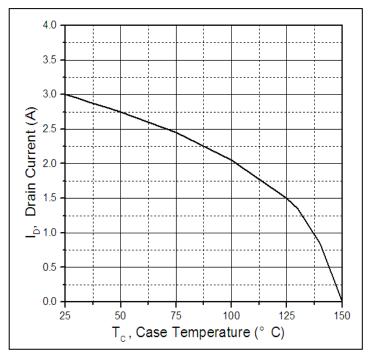
Figure 4: Normalized On-Resistance Vs. Case **Temperature**

Version: 1.0

20



Typical electrical and thermal characteristics



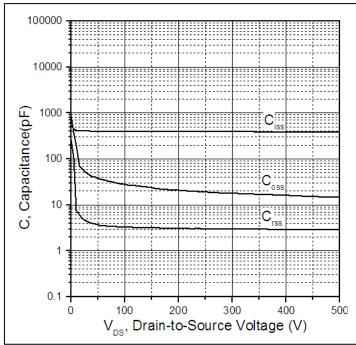


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

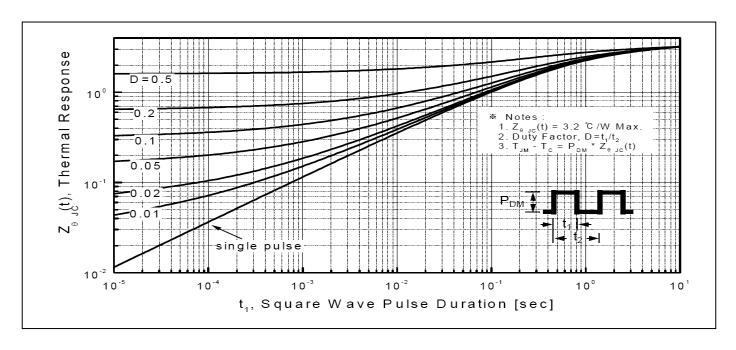
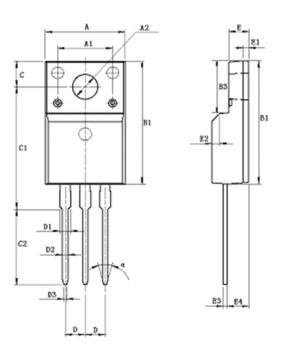


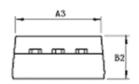
Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:

TO220F PACKAGE OUTLINE DIMENSION





Cumb al	Dimension In Millimeters			Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max	
Α	9.960	10.160	10.360	0.392	0.400	0.408	
A1		7.000		0.276	0.000	0.000	
A2	3.080	3.180	3.280	0.121	0.125	0.129	
A3	9.260	9.460	9.660	0.365	0.372	0.380	
B1	15.670	15.870	16.070	0.617	0.625	0.633	
B2	4.500	4.700	4.900	0.177	0.185	0.193	
B3	6.480	6.680	6.880	0.255	0.263	0.271	
С	3.200	3.300	3.400	0.126	0.130	0.134	
C1	15.600	15.800	16.000	0.614	0.622	0.630	
C2	9.550	9.750	9.950	0.376	0.384	0.392	
D		2.54 (TYP)		1.00 (TYP)			
D1	-	-	1.470	-	-	0.058	
D2	0.700	0.800	0.900	0.028	0.031	0.035	
D3	0.250	0.350	0.450	0.010	0.014	0.018	
E	2.340	2.540	2.740	0.092	0.100	0.108	
E1	0.700				0.028		
E2	1.0*45 ⁰				1.0*45 ⁰		
E3	0.450	0.500	0.600	0.018	0.020	0.024	
E4	2.560	2.760	2.960	0.101	0.109	0.117	
Θ		30 ⁰			30°	_	





Ordering and Marking Information

Device Marking: SSF3N80F

Package (Available)
TO220F
Operating Temperature Range
C: -55 to 150 °C

Devices per Unit

Package	Units/	Tubes/Inner	Units/Inner	Inner	Units/Carton
Type	Tube	Box	Box	Boxes/Carton	Box
				Box	

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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